





AT WAVELENGTH λ , MEASURE REFLECTANCE, mR, OF SAMPLE WITH KNOWN ABSOLUTE RELECTANCE, aR. STORE VALUES OF λ , mR AND aR

DIVIDE mR BY aR TO OBTAIN SYSTEM EFFICIENCY COEFFICIENT, Z λ , AT WAVELENGTH λ

STORE ZA IN MEMORY

WITH SAME OPTICAL SYSTEM AND SAME WAVELENGTH MEASURE REFLECTANCE, mRx, OF SAMPLE, x

DIVIDE [MULTIPLY] mRx BY Zλ TO OBTAIN ABSOLUTE REFLECTANCE, aRx, OF SAMPLE x